

attachment to PTOL - 413  
(do NOT detach)

NAKANO et al., SN 10/075,244  
19 October 2005 Amendment  
Reply to 19 July 2005 Office Action

501.41175X00 | 340101349US1  
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IN THE CLAIMS:

Proposal - 6/12/06

1. (Currently Amended) A method for processing a specimen using a plasma, comprising:

generating a plasma in a processing chamber in which the specimen is disposed; and

5 processing the specimen with the plasma generated in the processing chamber, wherein

the processing of the specimen comprises:

an irradiation operation for projecting and scanning a light beam into the processing chamber through an observation window of the processing chamber;

10 a detection operation for detecting a light of the projected light beam which is  
REFLECTED LIGHT SIGNAL CORRESPONDING TO A REFLECTED  
REFLECTED  
reflected from an inside wall of the processing chamber, the light being detected by  
WALL - REFLECTED  
separating a light component from light emanated from the plasma and light reflected  
from the inside wall by use of a spectroscope; and

15 a signal processing operation for obtaining information on a state of  
THE WALL-REFLECTED LIGHT  
contamination of the inside wall of the processing chamber, by processing a signal  
AN ELECTRONIC  
obtained at the detection operation by referring to a database storing predetermined  
CANDIDATE OBTAINABLE  
relationships between a signal signals obtained from said detection of light from said  
corresponding INSIDE-WALL  
inside wall and a state states of contamination of said inside wall.

TO DERIVE A STATE OF CONTAMINATION  
CORRESPONDING TO THE WALL-REFLECTED LIGHT  
SIGNAL, FROM THE ELECTRONIC DATABASE.

2. (Previously Presented) A method for processing a specimen using a plasma according to Claim 1, comprising